



Advanced Spectral Imaging Applications: Characterization, Detection and Classification

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Message from the Guest Editor

Advanced spectral imaging technologies are fundamental tools for the development of many fields. They are extensively applied in fields such as biology, geography, agriculture, medical treatment, military, printing industry, aerospace, etc. Specifically, spectral information can be utilized for geological detection, material classification, component analysis, remote sensing imaging, color reproduction, and so on. Therefore, this Special Issue aims to present advanced spectral imaging technologies and applications, including new methods and experimental results from theoretical research to application.

This Special Issue focuses on, but is not limited to, ultraviolet, visible, and infrared spectral imaging technologies, multi-spectral and hyper-spectral imaging, applications in characterization, detection, classification, remote sensing, and color reproduction, as well as other issues in spectral imaging and applications.





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Message from the Editor-in-Chief

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